

# Macroelectronics

Robert H. Reuss, Darrel G. Hopper, and  
Jae-Geun Park, Guest Editors

## Abstract

As revolutionary as microelectronics has been as a technology, there are functions that it does not address. Microelectronics focuses on ever-smaller integrated circuits (ICs) in ever-fewer square millimeters of space to increase clock speeds and decrease the power required for computer processing functions. However, applications requiring control, communications, computing, and sensing over a large area are difficult or cost-prohibitive to achieve because of the material incompatibilities of traditional ICs with structures, materials, and manufacturing technology. Macroelectronics addresses these applications with the aim of providing active control circuitry *in situ* over areas of many square meters for displays, solar panels, x-ray imagers, surface measurements, structural shape control, vehicle health monitoring, and other large-system applications. The materials challenges of macroelectronics integrated circuits (MEICs) reviewed in this issue include lightweight flexible substrates, thin-film transistors (TFTs) with IC or near-IC performance, modeling, and manufacturing technology. Compatible component materials, flexible substrates, processing conditions, host system composition, and functionality provide grand challenges that are just beginning to be addressed by researchers.

**Keywords:** *electronic material, lithography, sensor.*

Electronic devices have become increasingly pervasive over the last 50 years. Advances have been driven primarily by microelectronics, based on the well-known Moore's law that describes the increasing complexity (and therefore performance) as feature size decreases over time. While there are many issues to be addressed, as described by ITRS roadmap,<sup>1</sup> the mainstream microelectronics industry continues to provide ever-increasing performance and functionality. However, other forms of electronics have also become important, as they address problems that conventional microelectronics cannot. The most significant of these is the display industry, which now rivals the integrated-circuit (IC) industry in terms of revenue. The technical drivers for these two major industries are essentially opposite. While the IC industry strives to make the smallest possible devices in the smallest possible area, the display industry is interested in large devices over the largest possible area. This drive to distribute the devices over large areas can be considered "macroelectronics," because neither the active devices nor the area they cover needs to be "micro" in scale.

Commercially viable macroelectronics began in 1988 with thin-film-transistor-based liquid-crystal displays (TFT-LCDs). Direct-view active-matrix liquid-crystal

displays (AMLCDs) based on inorganic TFTs on glass substrates represent the first commercial success of macroelectronics. Sales of AMLCDs have superseded the cathode-ray tube in both revenue (2002) and units (2004) to become the dominant display technology on the planet.<sup>2</sup> Examples include the demonstration by Samsung in 2005 of an 82-in.-diagonal screen with six million TFTs controlling the brightness of each of two million color pixels (see Figure 1); a 100-in. AMLCD, announced by LG.Philips LCD Co. in January 2006; and an IBM monitor product introduced in 2002 with a 22.2-in.-diagonal screen, 27 million TFTs controlling 9.1 million (3840 × 2400) color pixels, and a TFT vertical/horizontal pitch of 124.5/41.5 μm. These TFT pitches are about a thousand times larger than those found in ICs. This difference in transistor density may be used as one way to distinguish macroelectronics ICs (MEICs) from classical metal oxide semiconductor field-effect transistor ICs.

Beyond the dominant AMLCD technology, several niche display technologies also use TFT backplanes to drive pixels over large areas and thus are considered examples of macroelectronics. Examples include displays based on organic light-emitting devices, electroluminescent elec-

trophoretic ink, and field-emission mechanisms. Other large-area display technologies are not macroelectronics, as they do not have MEICs built into them. Examples include inorganic light-emitting diodes (LEDs), vacuum cathode-ray tubes (CRTs), and most plasma technologies. The LEDs now popular for jumbo-size outdoor displays in stadiums, billboards, and building facades are not macroelectronics, because they are driven externally by personal computers, not internally by TFT MEICs. The CRT vacuum technologies are driven by analog electronics (e-guns and deflection coils) and are not even digital, let alone macroelectronic. Drive voltages and power are also a distinguishing factor: TFT technologies typically operate at 3–5 V, drawing 1–10 W, compared with 1–20 keV and 1–10 kW, variously, for plasma, CRT, and LED displays. The pixel size in LEDs and plasma are also issues: millions of LEDs are separately packaged and hand-mounted with 10-mm pitch in arrays meant for viewing at hundreds of feet.

Some potential future application areas for macroelectronics are illustrated in Figure 2. These areas include displays (top left and top right), sensors (top right and bottom right), energy harvesting (top right and bottom left), electronics embedded into gear (radios, range finders, computers) and clothing (bottom left), and structural health monitoring of vehicles or humans (bottom right). Structural health monitoring involves a range of sensors, processors, and transmitters built with flexible MEICs within vehicle composite materials to actively sense and report faults, or mounted on/in human biomaterials (skin/tissues) to continuously sense and transmit physiological and cognitive status. The weight and materials integration issues with ICs make these applications impossible or unlikely with a purely microelectronics approach and thus require macroelectronics.

The biggest challenge for macroelectronics technology is to enable applications beyond displays that involve large areas and volumes that cannot be cost-effectively achieved through traditional packaged-chip fabrication followed by pick-and-place assembly and that nonetheless require sophisticated, high-performance circuits. The large scale of macrosystems gives rise to the requirement for properties heretofore not associated with IC applications, such as thinness, ductility, and elasticity of electronic components, even during operation. Depending on specific applications, some design rules for traditional ICs must be maintained (e.g., length of transistor channels) and others relaxed (e.g., area of circuit layout).



Figure 1. Samsung 82-in. 2-megapixel (Mpx) active-matrix liquid-crystal display (AMLCD) next to a 102-in. 2-Mpx plasma display panel at the Society for Information Display Exhibition in May 2005. The AMLCD has 6 million thin-film transistors in its subpixels and is an example of the state of the art in macroelectronics manufacturing technology for full high-definition (HD) digital television displays. A 100-in. 2-Mpx AMLCD was announced in January 2006 by LG.Philips LCD Co. (Photograph courtesy of D.G. Hopper.)

While displays have already become a dominant force in electronics over the last few years, other trends have emerged that do not have the same success criteria as conventional electronics. One such area is new materials and devices for radio-frequency identification (RFID) tags. Here, the interest is not in performance, but in the lowest possible price, so that “disposable” electronics becomes possible. There is growing interest in other nontraditional product drivers, including light weight for portability, distribution over large surface areas for measurement and control functions, and flexibility to allow the electronics to be conformed to a 3D surface or folded for ease of transport. All of these desirable qualities are characterized by attributes that are significantly different than the number of transistors/cm<sup>2</sup> that drives classic microelectronics.

In this issue of *MRS Bulletin*, we provide a snapshot of some of the major trends in macroelectronics. Primarily, our overview is from the perspective of active devices, which are the key enablers of this emerging technology. Additional technology challenge areas for macroelectronics include substrates, dielectrics, and sealing. These issues are addressed to some extent within the articles in this issue, but the reader is also referred to the many articles on these topics published by the Society for Information Display, and to the U.S. Army flexible display initiative described by Pellegrino et al.<sup>3</sup>

Macroelectronics often involves co-fabrication of electronics and structures. An MEIC is typically built directly onto or within the structure it controls, senses, or communicates with. The ultimate MEIC is inseparable from and synergistic with the system in which it resides—like the nervous system within a human body. The opposite is true for traditional microelectronics, in which passive devices, packaged chips, boards, and boxes are each fabricated separately and only later are integrated into the structure to be operated or interfaced with. This difference in systems engineering approach has profound implications for the materials, electronic design, and manufacturing techniques required. The TFT MEICs in active-matrix displays must be built in during the manufacturing process of the display for it to work—you cannot just append an IC later. The TFT MEICs used in aircraft structural health monitoring must be built into the composite materials. The weight, volume, and materials compatibility (e.g., flexibility) of packaged ICs preclude their use for this application.

One very desirable feature is to apply integrated electronics to flexible substrates

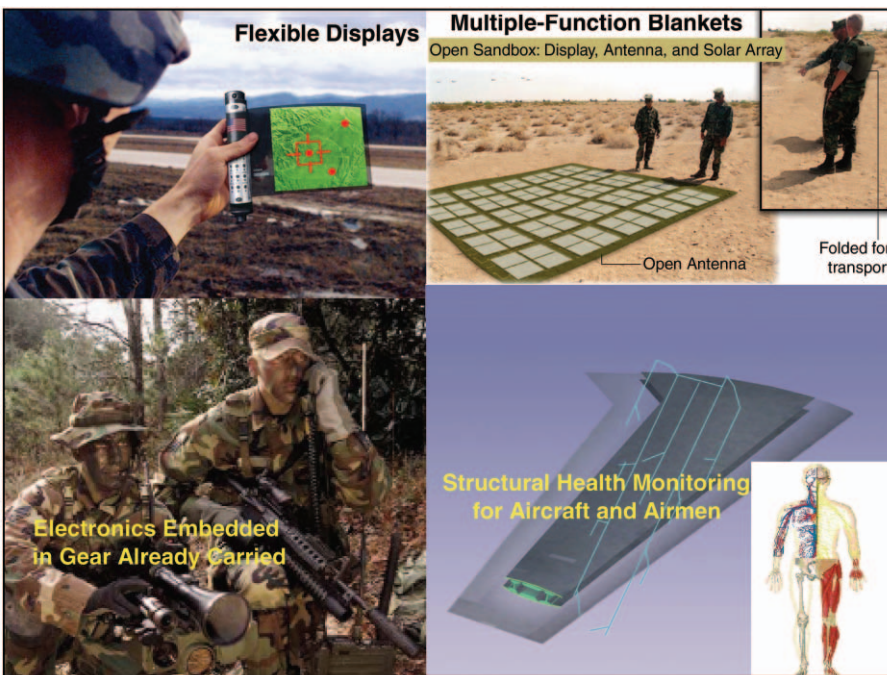


Figure 2. Examples of conceptual future applications envisioned for macroelectronics. (Photograph courtesy of D.G. Hopper.)

in the anticipation that this achievement would dramatically increase applications that could be addressed. Envisioned macroelectronics applications include covering exposed surfaces (e.g., airframes, walls), integration into mechanical structural elements to conserve space and weight (buildings, airships, unmanned aerial vehicles, clothing), and control/sensor applications. Furthermore, with a flexible substrate, the electronics package could be folded or rolled up for storage when not in operation.

Organic TFTs (OTFTs) may have better compatibility, in terms of coefficients of expansion, with composite materials in which they may be embedded for applications such as structural health monitoring in aircraft. In this *MRS Bulletin* issue, Lee et al. from Samsung discuss OTFTs, with a particular emphasis on display applications. The authors review OTFTs for large-size displays and demonstrate that their unique solution-processable gate dielectric materials form uniform films over large areas and exhibit excellent insulating properties and reduced contact resistance. A 15-in. full-color AMLCD and 192 × 64 pixel active-matrix organic LEDs driven by pentacene-based OTFTs have been demonstrated for the first time. Optimization of these materials for organic semiconductor patterning creates an opportunity to develop commercially viable flexible MEICs.

Transistors for macroelectronics cannot be made with the thick-film designs and high-temperature processes used to make traditional small (10 mm × 10 mm) IC chips on small (300 mm) rigid substrates in an expensive fabrication facility; TFT designs must be used instead. The TFT was invented by Weimer<sup>4</sup> in 1962 at the RCA Laboratories (now Sarnoff Corp.) for the purpose of implementing the IC concept, but its main application has been as a pixel switch and driver circuitry running at kilohertz speeds for active-matrix flat-panel displays based on liquid-crystal light modulation. These applications have not forced TFT research to produce the higher device performance in speed (megahertz, gigahertz), scale, or cost that will often be needed for MEICs. Thus, producing TFTs with IC-quality performance is a technical challenge that macroelectronics must address. Near-IC performance at a throw-away low cost is another.

Recent work by Brotherton et al.<sup>5</sup> at Philips in the United Kingdom has shown that TFTs with channel lengths similar to ICs are possible; the Philips goal is to move all electronics into the display. Furthermore, these high-performance TFTs must be compatible with all other MEIC properties (e.g., flexible substrate) or have other

novel characteristics (e.g., transparency). The group led by Wager<sup>6</sup> has invented transparent TFTs (TTFTs) based on a novel new class of semiconductors known as amorphous multicomponent heavy-metal cation (a-MHMC) oxides (see Figure 3).

However, it has proven very difficult to achieve high-performance TFTs and macroelectronics on plastic substrates. In this issue, van der Wilt et al. from Columbia University and Sarnoff Corp. discuss poly-Si TFT circuit fabrication directly on a plastic substrate, which is the most advanced and highest-performance technology achieved to date, as measured by unity gain frequencies  $f_t$  of 250 MHz and 185 MHz for *n*-type and *p*-type metal oxide semiconductor TFTs and by CMOS ring oscillators above 100 MHz.<sup>8</sup>

The challenges for fabricating high-quality, poly-Si TFTs, especially on low-temperature substrates, are daunting. For that reason, alternative methods such as the OFETs are of considerable interest. But the difficulty of obtaining organic-based TFTs with adequate device characteristics has led to the search for new ways to fabricate crystalline, inorganic semiconductors on lightweight and low-cost substrates. Examples of this approach include carbon nanotubes and silicon nanowires. As these devices have novel compositions and structures, yet are analogous to classical transistors, theory, modeling, and circuit simulation tools need to be adapted from the IC and flat-panel display industries and expanded to address the peculiarities of macroelectronics circuits. In their article, Alam et al. from Purdue University address the issue of modeling these new device structures such that the rapidly expanding experimental results can be used to predict and develop future macroelectronics materials, structures, and devices.

Manufacturing advanced MEICs requires a new fabrication industry based on techniques that are currently alien to microelectronics processing. Roll-to-roll substrate handling replaces wafer batches; material deposition via printing replaces vacuum evaporation; material removal by stamping replaces etching, and self-assembly re-

places deterministic, submicrometer-scale placement of components. The capital required to build a microelectronics state-of-the-art 300-mm wafer fabrication facility is \$3 billion; macroelectronics facilities are anticipated to cost an order of magnitude less. Furthermore, the cost pure unit area of product is expected to drop from the order of \$10,000 per sq ft for microelectronics to \$100 per sq ft for macroelectronics. An initial approach to this alternative means of manufacture is presented by Chason et al. from Motorola in their description of adopting printing techniques and circuit board technologies for large-area, low-cost macroelectronics for applications such as telecommunications products.

To achieve both the technical and cost goals for high-performance macroelectronics, patterning techniques are needed for MEICs that include dynamic self-alignment to 1 μm or less over more than 300 mm of stretchable/shrinkable substrate, rather than 100 nm or less over 0.3 m of rigid substrate in ICs. While the design rule tolerance may be relaxed 10× in many cases for an MEIC compared with a traditional IC, the substrate scale grows by 1000×. Also, macroelectronics substrates may not be rectilinear flat. These capabilities are expected to be significant enablers of future macroelectronics products.

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3. J.M. Pellegrino, G.L. Wood, D.C. Morton, and E.W. Forsythe, in *Proc. SPIE 5080* (SPIE, Bellingham, WA, 2003) p. 1.
4. P.K. Weimer, in *Proc. IRE 50* (1962) p. 1462. Working at the RCA Laboratories (now Sarnoff Corp.), Weimer fabricated integrated thin-film circuits incorporating passive elements and hundreds of thin-film transistors (TFTs) operating in enhancement, with the first semiconductor films for TFTs being CdS. Weimer's experience with *n*- and *p*-type TFTs led him to the invention of the low-power complementary inverter and the flip-flop circuit, both now widely used in CMOS silicon memories. Although the TFT approach to integrated circuits was displaced by *x*-Si for most applications, the advantage of the TFT for large-area circuits was apparent. Also, Weimer thought it fun to challenge the silicon establishment with an alternative approach.
5. S.D. Brotherton, C. Glasse, C. Glaister, P. Green, F. Rohlfing, and J.R. Ayres, *Appl. Phys. Lett.* **84** (2) (2004) p. 293. Working at the Philips

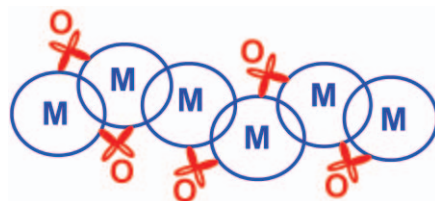


Figure 3. Schematic illustration of an amorphous multicomponent heavy-metal cation oxide.<sup>7</sup>

Research Laboratories in the United Kingdom, Brotherton et al. have focused on increasing circuit integration in active-matrix liquid-crystal displays (AMLCDs) with the ultimate goal of system-on-panel displays. Achievement of this goal requires the replacement of metal oxide silicon field-effect transistor (MOSFET) circuits with poly-Si thin-film transistor (TFT) circuits. The key difference between MOSFETs and TFTs is the channel length: production MOSFET channels are submicrometer in size, while TFT channels are 4–6  $\mu\text{m}$ . Brotherton et al. demon-

strated 0.5- $\mu\text{m}$  channel-length TFTs with a 20-nm-thick gate oxide with high mobilities ( $\mu_p = 60 \text{ cm}^2/\text{V s}$ ,  $\mu_n = 80 \text{ cm}^2/\text{V s}$ ) and with gigahertz potential ( $\sim 0.1 \text{ ns delay/stage}$  at 3 V supply for a 15-stage complementary-pair MOSFET ring oscillator).

6. J. Wager's group at Oregon State University and Hewlett Packard in Corvallis, Oregon, have begun to investigate amorphous multicomponent heavy-metal cation (a-MHMC) oxides for transparent thin-film transistor (TTFT) applications. Initial results are reported in Dehuff et al.,

*J. Appl. Phys.* **97** 064505 (2005) and Chaing et al., *Appl. Phys. Lett.* **86** 013503 (2005). For example, 85% transmission of visible light was obtained for zinc indium oxide (ZIO) TTFTs made at 300°C having a mobility  $\mu$  of 10–30  $\text{cm}^2/\text{V s}$  and an on/off ratio of 106.

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**Robert H. Reuss**, Guest Editor for this issue of *MRS Bulletin*, joined the U.S. Defense Advanced Research Projects Agency as a program manager in the Microsystems Technology Office in 2001 and is responsible for several research thrusts including macroelectronics, ultralow-power device/circuit technology, and tools for reduced design time and cost for complex integrated circuits. He received his PhD degree in chemistry from Drexel University in 1971. Prior to joining DARPA, he spent 20 years in various technology and research management positions within Motorola Inc.

Reuss has been elected to Motorola's Science Advisory Board, is a member of the Materials Research Society, and is a senior member of IEEE. He has published more 50 papers and holds 13 U.S. patents.

Reuss can be reached at DARPA, 3701 N. Fairfax Drive, Arlington, VA 22203 USA; tel. 703-696-2214 and e-mail rreuss@darpa.mil.

**Darrel G. Hopper**, Guest Editor for this issue of *MRS Bulletin*, is principal electronics engineer at the U.S. Air Force Research Laboratory. He received his PhD degree in physical chemistry in 1971 from

Oklahoma State University. Following a post-doctoral appointment in biochemistry, he performed basic research in molecular electronics until 1982, when he transitioned to applied electro-optics. He has worked as a physicist at the National Air Intelligence Center and professor of electronics engineering at the Air Force Institute of Technology.

Hopper has more than 260 publications in chemistry, physics, and electronics. He is a fellow of SPIE, a senior member of IEEE, and a senior member and director of the Society for Information Display.

Hopper can be reached at the Air Force Research Laboratory, AFRL/HECV Bldg. 248 Rm. 300, 2255 H St., Wright-Patterson AFB, OH 45433-7022 USA; tel. 937-255-8822 and e-mail darrel.hopper@wpafb.af.mil.

**Jae-Geun Park**, Guest Editor for this issue of *MRS Bulletin*, is a senior research staff member in the Materials Center at Samsung Advanced Institute of Technology (SAIT). He received a BS degree in chemistry from Seoul National University in 1983 and MS and PhD degrees in polymer chemistry from Korea Advanced Institute of Science and Technology in 1984 and 1988,



Robert H. Reuss

respectively. He worked as a director of the E-Polymer Laboratory at SAIT, where he was involved in the development of polymeric electronic materials. He was also a visiting scientist in the Department of Materials Science and Engineering at the University of Illinois at Urbana-Champaign from 2003 to 2005. His current research is focused on functional polymers and organic/inorganic composite materials for flexible and printable electronic devices.

Park can be reached at Samsung Advanced Institute for Technology (SAIT), Materials Lab, Mt. 14-1, Nongseo-ri, Giheung-eup, Yongin, Gyeonggi-do, 449-712 Korea; tel. 82-31-280-6742, fax 82-31-280-9349, and e-mail jaegeun.park@samsung.com.

**John R. Abelson** is a professor of materials science and engineering at the University of Illinois at Urbana-Cham-



Darrel G. Hopper

paign. He received a BS degree from Yale University in 1979 and performed research at the Solar Energy Research Institute from 1979 to 1981 and at the Ecole Polytechnique in Paris the following year. He then earned a PhD degree in materials science from Stanford University in 1987. He joined the faculty at Illinois in 1988. His research work concerns electronic materials, the atomistic mechanisms of thin-film growth, CVD of transition-metal diborides, nanoscale order in amorphous materials, and phase-change chalcogenides for data storage. He has published more than 100 peer-reviewed papers, supervised 12 PhD dissertations, and is a fellow of the AVS.

Abelson can be reached at the University of Illinois at Urbana-Champaign, Department of Materials Science and Engineering, 1-109 Engineering Science Bldg.,



Jae-Geun Park

1101 W. Springfield Ave., Urbana, IL 61801 USA; tel. 217-333-7258, fax 217-244-1631, and e-mail abelson@mrl.uiuc.edu.

**Muhammad A. Alam** is a professor of electrical and computer engineering at Purdue University. He received a BSEE degree from Bangladesh University of Engineering and Technology in 1988, an MS degree from Clarkson University in 1991, and a PhD degree from Purdue University in 1994, all in electrical engineering. He was with Bell Laboratories/Lucent Technologies from 1993 to 2001, and from 2001 to 2003, he was a distinguished member of technical staff at Agere Systems. He joined Purdue in 2004. Alam's current research includes theory of oxide reliability, transport in nanocomposite thin-film transistors, and nanobio sensors. He is an IEEE fellow and a recip-



John R. Abelson



Muhammad A. Alam



Paul W. Brazis Jr.



Marc Chason



Adrian M. Chitu



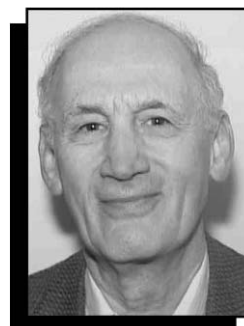
Robert Crosswell



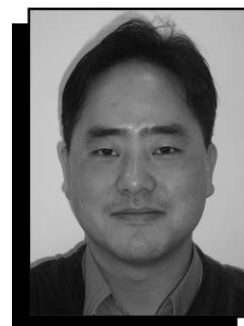
Arthur H. Firester



Daniel R. Gamota



Lawrence Goodman



Jungseok Hahn

ient of the IEEE Kiyo Tomiyasu Award for contributions to optoelectronic devices.

Alam can be reached at Purdue University, School of Electrical and Computer Engineering, EE313D, 465 Northwestern Ave., West Lafayette, IN 47906 USA; tel. 765-494-5988, fax 765-494-6441, e-mail [alam@purdue.edu](mailto:alam@purdue.edu), and URL [dynamo.ecn.purdue.edu/~alam](http://dynamo.ecn.purdue.edu/~alam).

**Paul W. Brazis Jr.** is a senior staff electrical engineer at Motorola Labs. He received his PhD in electrical engineering in 2000 from Northwestern University and then joined Motorola, where he is currently leading the semiconductor device, circuit design, and characterization efforts in printed electronics.

Brazis was vice chair for the IEEE standards 1620-2004<sup>TM</sup>, 1620.1-2006<sup>TM</sup>, and 1650-2005<sup>TM</sup>, and serves as vice chair of the IEEE standards

working group P1620.2. He was also co-organizer of the IMAPS-sponsored "Printing an Intelligent Future" workshops and is a co-inventor on eight U.S. patents. He has authored or co-authored more than 45 publications and over 50 conference and poster presentations.

Brazis can be reached at Motorola Inc., 1301 E. Algonquin Rd., IL02, Rm. 1014, Schaumburg, IL 60196 USA; tel. 847-576-1561, fax 847-576-2111, and e-mail [paul.brazis@motorola.com](mailto:paul.brazis@motorola.com).

**Marc Chason** is a fellow of the technical staff and director of the Step-Change Nanotechnology Laboratory in the Physical Realization Research Center, a part of Motorola Labs. He received his MS degree from SUNY Stony Brook in 1974 and was employed at Argonne National Laboratory until 1983. He then joined Mo-

torola, where he has worked in numerous fields, including the development of printed electronics. He has authored or co-authored more than 30 internal and external papers, holds 21 U.S. patents, and in 1997 became a Motorola Dan Noble Fellow, Motorola's highest technical honor.

Chason can be reached at Motorola Inc., 1301 E. Algonquin Rd., IL02, Rm. 1014, Schaumburg, IL 60196 USA; tel. 847-538-9952, fax 847-576-2111, and e-mail [marc.chason@motorola.com](mailto:marc.chason@motorola.com).

**Adrian M. Chitu** has worked as a research technician in the Laser Crystallization Laboratory at Columbia University since 2002 and is currently pursuing a graduate degree in materials science and engineering. He graduated in 1992 with a bachelor's degree in electronic engineering from Poly-

technic University of Bucharest in Romania. After graduation, he worked in the Laser Department at the Atomic Physics Institute in Bucharest on data-acquisition systems involving pulsed lasers. His current research centers on the use of transient measurements to analyze rapid melting and solidification phenomena in thin films.

Chitu can be reached at Columbia University, Department of Applied Physics and Applied Mathematics, Laser Crystallization Lab, 1106 Mudd, Mail Code 4711, 500 W. 120th St., New York, NY 10027 USA; tel. 212-854-8761, fax 212-854-9010, and e-mail [ac2224@columbia.edu](mailto:ac2224@columbia.edu).

**Robert Crosswell** is a principal staff electrical engineer at Motorola Labs. He received his PhD degree from North Carolina State University in 1998. He then spent a year as a post-

doctoral associate directing NCSU's 6-in. silicon cluster tool laboratory, prior to joining Motorola Labs in 1999. His current research activities at Motorola include embedded passive components and electronic bandgap surfaces.

Crosswell has published eight refereed journal articles and co-authored 15 conference proceedings and trade journal articles. He holds three U.S. patents.

Crosswell can be reached at Motorola Inc., 1301 E. Algonquin Rd., IL02, Rm. 1014, Schaumburg, IL 60196 USA; tel. 847-576-6521, fax 847-576-2111, and e-mail [robert.crosswell@motorola.com](mailto:robert.crosswell@motorola.com).

**Arthur H. Firester** is an independent technology management consultant. He received his MA and PhD degrees in physics from Princeton University. His technical expertise, both participatory and managerial, in-



James S. Im

cludes optical spectroscopy, holography, lasers, and nonlinear optics; optical recording; display device production, engineering, and instrumentation; amorphous silicon solar cells research, fabrication, and application; microwave materials, devices, applications, and systems; applied mathematics and physics focused on physical system simulation and electron optics design; flat-display technologies including amorphous silicon, polysilicon, transfer silicon, and organic thin-film transistor AMLCD and AMEL displays; field-emission displays; and virtual reality software and hardware systems.

Firester has authored numerous scientific papers. He holds more than 20 U.S. patents and has over 30 years' experience in research and program management.

Firester can be reached at 24 Lakeview Dr., Skillman, NJ 08558 USA; tel. 609-466-2057 and e-mail [afirester@patmedia.net](mailto:afirester@patmedia.net).

**Daniel R. Gamota** is a distinguished member of technical staff in the Motorola Labs Physical Realization Research Center. He has a PhD degree from the University of Michigan and an MBA from Northwest



Krishna Kalyanasundaram

ern University. He joined Motorola in 1993 and is currently manager of the Printed Electronics Solutions Team, developing novel inks and processing methods to print integrated circuits for low-cost wireless products.

Gamota was named a Motorola Dan Noble Fellow in 2003, Motorola's highest technical honor. He holds 26 U.S. patents, has published 12 articles on microelectronics technology, and co-edited *Printed Organic and Molecular Electronics*.

Gamota can be reached at Motorola Inc., 1301 E. Algonquin Rd., IL02, Rm. 1014, Schaumburg, IL 60196 USA; tel. 847-576-5084, fax 847-576-2111, and e-mail [gamota@motorola.com](mailto:gamota@motorola.com).

**Lawrence Goodman** recently rejoined Sarnoff Corp. as a senior member of technical staff after four years as an independent consultant and vice president of engineering for Sarcon Corp., which focused on the development of uncooled infrared-imaging products based on the integration of infrared-sensitive, micro-cantilever arrays. Goodman had previously been an employee of Sarnoff and its predecessor organization, RCA Laboratories, for 30 years



Michael G. Kane

in various technical and managerial positions. He received his academic degrees from the Massachusetts Institute of Technology.

During his years at Sarnoff, he developed the processing technology for RCA's power MOSFETs and IGBTs and played a leading role in the development of passive and active-matrix-addressed LCDs, including the fabrication of the first amorphous-silicon TFTs for this application. Goodman received four Sarnoff achievement awards for his technical contributions. He is the author of 25 technical publications and holds 22 U.S. patents.

Goodman can be reached at Sarnoff Corp., 201 Washington Rd., CN5300, Princeton, NJ 08543 USA; tel. 609-720-4933 and e-mail [lgoodman@sarnoff.com](mailto:lgoodman@sarnoff.com).

**Jungseok Hahn** is a member of the research staff in the Printable TFT Strategic Technology Unit at Samsung Advanced Institute of Technology (SAIT). He received BS degrees in mathematics and chemistry at the University of Missouri-Columbia and an MS degree in mathematics at Washington University in St. Louis. He also holds MS and PhD degrees in polymer



Jong Min Kim



Satish Kumar

material chemistry from the University of Texas at Austin for work on ordering properties of polymeric micelles on surfaces. Following a postdoctoral appointment at UT-Austin, he accepted his current position and is working on surface modification, self-assembly, and particle ordering for organic devices.

Hahn is a recipient of the ACS Award in Analytical Division and a winner of the Putnam Math Competition. He can be reached at Samsung Advanced Institute of Technology, Mt. 14-1, Nongseo-ri, Giheung-eup, Yongin, Gyeonggi-do, 446-712 Korea; tel. 82-31-280-6745, fax 82-31-280-6725, and e-mail [j.hahn@samsung.com](mailto:j.hahn@samsung.com).

**James S. Im** is a professor in the Department of Applied Physics and Applied Mathematics at Columbia University. He received his PhD degree in electronic ma-



Bonwon Koo



Sangyun Lee

terials from the Massachusetts Institute of Technology in 1989 and worked as a postdoctoral research fellow at the California Institute of Technology until 1991. In that same year, he joined Columbia as an assistant professor and has served as the chair of the materials science and engineering program since 1998.

Im has been investigating various aspects of energy- and particle-beam-induced phase transformations since 1984. His research interests include laser-induced melting and solidification of thin films and nucleation in condensed systems.

Im can be reached at Columbia University, Department of Applied Physics and Applied Mathematics, Laser Crystallization Lab, 1106 Mudd, Mail Code 4711, 500 W. 120th St., New York, NY 10027 USA; tel. 212-854-8341, fax 212-854-9010, and e-mail [ji12@columbia.edu](mailto:ji12@columbia.edu).



**Keryn K. Lian**



**Alexander B. Limanov**



**Hyunsik Moon**



**Jayathi Murthy**



**Ninad Pimparkar**



**Paul C. van der Wilt**



**Jie Zhang**

**Krishna Kalyanasundaram** is a principal staff engineer at Motorola Labs. In 1995, he received bachelor's and master's degrees from Birla Institute of Technology and Science in Pilani, India, and in 1997, he received a master's degree from SUNY Binghamton. He joined Motorola in 1997 and is currently working toward merging microelectronics and graphic arts printing to create low-cost printed electronics products.

Kalyanasundaram has co-organized or chaired sessions for the IMAPS-sponsored "Printing an Intelligent Future" workshops and holds four U.S. patents.

Kalyanasundaram can be reached at Motorola Inc., 1301 E. Algonquin Rd., IL02, Rm. 1014, Schaumburg, IL 60196 USA; tel. 847-576-9596, fax 847-576-2111, and e-mail [krishnak@motorola.com](mailto:krishnak@motorola.com).

**Michael G. Kane** is a distinguished member of technical staff at Sarnoff Corp. He received his PhD degree in electrical engineering from Princeton University. Before joining Sarnoff in 1994, he was leader of the Ultrafast All-Optical Switching Project at Siemens Corporate Research and head of the GaAs IC Design Group at Microwave Semiconductor Corp. He has also served as a visiting faculty member in the Department of Electrical Engineering at Princeton, teaching courses in solid-state physics and solid-state displays. At Sarnoff, he has worked on organic and inorganic thin-film transistor technologies for flexible plastic active-matrix displays and electronic circuits. Kane is the author of more than 65 technical papers and holds 13 U.S. patents.

Kane can be reached at Sarnoff Corp., 201

Washington Rd., CN 5300, Princeton, NJ 08543 USA; tel. 609-734-3186, fax 609-734-2873, and e-mail [mkane@sarnoff.com](mailto:mkane@sarnoff.com).

**Jong Min Kim** is a Samsung fellow and director of the Displays Laboratory and Materials Center at Samsung Advanced Institute of Technology (SAIT). He received a BS degree from Hong-Ik University in Korea and MS and PhD degrees from the New Jersey Institute of Technology for work on the process development of field-emission displays (FEDs). After continuing his research on FEDs at the U.S. Army Research Laboratory and FED Corp., he accepted a team leader position at SAIT, developing carbon nanotube FEDs.

His current research focuses on novel devices and materials for displays and energy applications. He is a recipient of the Samsung Group Outstanding Technology Award, the SAIT Breakthrough Prize, and the Korea Science Technology Award.

Kim can be reached at Samsung Advanced Institute of Technology, Mt. 14-1, Nongseo-ri, Giheung-eup, Yongin, Gyeonggi-do, 446-712 Korea; tel. 82-31-280-9311, fax 82-31-280-9349, and e-mail [jongkim@samsung.com](mailto:jongkim@samsung.com).

**Bonwon Koo** is a member of research staff in the Printable TFT Strategic Technology Unit at Samsung Advanced Institute of Technology (SAIT). He received his BS and MS degrees in physics from Keimyung University and a PhD degree in electrical engineering from Dong-A University. His research interests include surface and interfacial properties in OTFTs and fabrication processes for flexible and large-area displays.

Koo can be reached at Samsung Advanced Institute of Technology, Mt. 14-1, Nongseo-ri, Giheung-eup, Yongin, Gyeonggi-do, 446-712 Korea; tel. 82-31-280-6741, fax 82-31-280-6725, and e-mail [bwkoo@samsung.com](mailto:bwkoo@samsung.com).

**Satish Kumar** is pursuing his PhD degree in mechanical engineering at Purdue University. He received a BTech degree in mechanical engineering from the Indian Institute of Technology, Guwahati, in 2001, and an MS degree from Louisiana State University, Baton Rouge, in 2003. His research interests are biofluids, computational fluid dynamics, and electrothermal transport in nanoscale devices. He is the recipient of the Purdue Research Fellowship for 2005–2006.

**Jaeseob Lee** was most recently a postdoctoral research associate in the Materials Science and Engineering Department at the University of Illinois at Urbana-Champaign.

Lee can be reached at the University of Illinois, Department of Materials Science and Engineering, Materials Science and Engineering Building, 1304 W. Green St., Urbana, IL 61801 USA; e-mail [jaeseob@uiuc.edu](mailto:jaeseob@uiuc.edu).

**Sangyun Lee** is leader of the Printable TFT Strategic Technology Unit at Samsung Advanced Institute of Technology (SAIT) and the SAIT master. He received BS and MS degrees in inorganic materials engineering from Seoul National University and a PhD degree from Stanford University. He is a recipient of the Korean Government Overseas Scholarship. He was a visiting researcher in the Advanced Materials Lab at Stanford, studying high- $\kappa$  oxides and ferroelectric domain structures. He also worked at Orioles Inc. on white LEDs and chemical-mechanical polishing, and led the organic TFT group for the flexible and large-area display project at SAIT, receiving the Best Practice Award as project man-

ager. He is currently in charge of printable TFT and low-temperature poly-Si projects at SAIT.

Lee can be reached at Samsung Advanced Institute of Technology, Mt. 14-1, Nongseo-ri, Giheung-eup, Yongin, Gyeonggi-do, 446-712 Korea; tel. 82-31-280-6756, fax 82-31-280-6725, and e-mail sangyoon.lee@samsung.com.

**Keryn K. Lian** is a distinguished member of technical staff at Motorola Labs. She received her PhD degree from the University of Toronto. For the last four years, she has been working on PWB-based MEMS-related research, primarily for RF switches and microfluidic systems. Previously, she performed research in electrochemical energy storage systems and was involved in automotive electronics. Lian has more than 20 publications and holds 33 U.S. patents.

Lian can be reached at Motorola Inc., 1301 E. Algonquin Rd., IL02, Rm. 1014, Schaumburg, IL 60196 USA; tel. 847-538-9532, fax 847-576-2111, and e-mail keryn.k.lian@motorola.com.

**Alexander B. Limanov** is a research scientist in the Department of Applied Physics and Applied Mathematics at Columbia University and is in charge of

Columbia's Laser Crystallization Laboratory. In 1988, he received his PhD degree in crystal physics from the Institute of Crystallography of the USSR Academy of Sciences in Moscow and continued his work at the Institute as a senior scientist. Since 1998, he has been working in the Laser Crystallization Laboratory. He has been investigating laser-induced crystallization of Si films since 1981, and his present laser crystallization research activities involve both fundamental as well as technology-oriented studies. He has published numerous papers on zone-melting recrystallization and line-scan sequential lateral solidification methods.

Limanov can be reached at Columbia University, Department of Applied Physics and Applied Mathematics, Laser Crystallization Laboratory, 1106 Mudd, Mail Code 4711, 500 W. 120th St., New York, NY 10027 USA; e-mail ab124@columbia.edu.

**Hyunsik Moon** is a member of research staff in the Printable TFT Strategic Technology Unit at Samsung Advanced Institute of Technology (SAIT). He holds BS and MS degrees in fiber and polymer science from Seoul National University in Korea and an MS degree in electrical engineering from the University of

Michigan, Ann Arbor. He received a PhD degree in macromolecular science and engineering from UM for his work on transport in organic field-effect transistors based on  $\pi$ -stacking oligomers and polymers. Following his postdoctoral work in chemistry at UM, he joined SAIT. His research focuses on printing processes and cross-linkable polymeric dielectrics for large-area displays. Moon received a Best Poster Award at the 2004 MRS Spring Meeting.

Moon can be reached at Samsung Advanced Institute of Technology, Mt. 14-1, Nongseo-ri, Giheung-eup, Yongin, Gyeonggi-do, 446-712 Korea; tel. 82-31-280-6745, fax 82-31-280-6725, and e-mail hyunsik.moon@samsung.com.

**Jayathi Murthy** is a professor of mechanical engineering at Purdue University. She received her PhD degree from the University of Minnesota and has worked in various areas of industry and academia. Her research interests include the development of unstructured finite volume methods for computational fluid dynamics and their application to a variety of physical and industrial problems, most recently in microscale heat transfer and thermal radiation. She serves on the editorial board of *Numerical Heat Transfer*

and is an editor of the *Handbook of Numerical Heat Transfer*.

Murthy can be reached at Purdue University, School of Mechanical Engineering, West Lafayette, IN 47907 USA; tel. 765-494-5701, fax 765-494-0539, and e-mail jmurthy@ecn.purdue.edu.

**Ninad Pimparkar** is working on his PhD degree at Purdue University. He received his BTech and MTech degrees from the Indian Institute of Technology in Bombay in 2003. His research interests include simulation, theory, and compact modeling of nanocomposite thin-film devices.

Pimparkar can be reached by e-mail at ninad@purdue.edu.

**Paul C. van der Wilt** is an associate research scientist in the Department of Applied Physics and Applied Mathematics at Columbia University. He received his doctorate degree in electrical engineering from Delft University of Technology in the Netherlands in 2003 and has since worked in Columbia's Laser Crystallization Laboratory. His research involves low-temperature polycrystalline Si TFT devices and, in particular, laser crystallization of Si films for large-area electronics and other advanced applications. Currently,

his research focuses on developing crystal-orientation-controlled single-crystal Si for ultrahigh-performance TFTs.

Van der Wilt can be reached at Columbia University, Department of Applied Physics and Applied Mathematics, Laser Crystallization Lab, 1106 Mudd, Mail Code 4711, 500 W. 120th St., New York, NY 10027 USA; tel. 212-854-9749, fax 212-854-9010, and e-mail pv2001@columbia.edu.

**Jie Zhang** joined Motorola Labs in 1996 and is currently a principal staff engineer, leading the materials characterization, printing technology assessment, printing processing development, and device fabrication efforts for printed electronics. She has authored or co-authored more than 30 journal and conference papers and one book chapter; co-edited *Printed Organic and Molecular Electronics*; and co-organized the IMAPS-sponsored "Printing an Intelligent Future" workshops in 2002, 2003, and 2004. She is also a co-inventor on eight U.S. patents.

Zhang can be reached at Motorola Inc., 1301 E. Algonquin Rd., IL02, Rm. 1014, Schaumburg, IL 60196 USA; tel. 847-538-6847, fax 847-576-2111, and e-mail jie.zhang@motorola.com. □

MRS FUTURE MEETINGS

See page 476 for meeting details!

2006 FALL MEETING

November 27-December 1  
Exhibit: November 28-30  
Boston, MA

Meeting Chairs:

**Babu R. Chalamala**  
Indocel Technologies, Inc.  
Tel 919-244-1040  
Fax 888-853-4407  
chalamala@indocel.net

**Louis J. Terminello**  
LLNL  
Tel 925-423-7956  
Fax 925-422-0029  
terminello1@llnl.gov

**Helena Van Swygenhoven**  
Paul Scherrer Institute  
Tel 41-56-310-2931  
Fax 41-56-310-3131  
helena.vs@psi.ch